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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete If Known	
				Application Number	10/672,961 (Conf. No. 9439)
				Filing Date	September 26, 2003
				First Named Inventor	Glenn J. Leedy
				Art Unit	2822
				Examiner Name	Monica Lewis
Sheet	1	of	1	Attorney Docket Number	ELM-2 CONT. 4

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
ML		DE3233195	03-17-1983	Mitsubishi Electric Corp.		
		JP2037655	02-07-1990	Siemens AG		
		JP3127816	05-30-1991	Canon KK		
		JP3174715	07-29-1991	Fujitsu Limited		
ML		WO 98/19337	05-07-1998	Trusi Technologies, LLC		

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁷
ML		Wolf, Stanley and Richard N. Tauber; Silicon Processing For the VLSI Era, Volume 1: Process Technology; Sunset Beach, CA: Lattice Press, 1986, pages 191-194	
		European Search Report for Application No. EP 02 00 9643 (date completed: October 8, 2002)	
		Phys. Rev. B., Condens. Matter Mater. Phys. (USA), Physical Review B (Condensed Matter and Materials Physics), 15 March 2003, APS through AIP, USA.	
ML		S. Wolf, Silicon Processing For the VLSI Era, 1990, Lattice Press, Volume 2, page 191.	
ML		Svechnikov, S.V.; Kobylatskaya, M.F.; Kimarskii, V.I.; Kaufman, A.P.; Kuzolev, Yu. I.; Cherepov, Ye. I.; Fomin, B.I.; "Switching Card With Aluminum Membrane Current Lead Crossovers"; 1972	
ML		Salazar, M.; Wilkins, C.W., Jr.; Ryan, V.W.; Wang, T.T.; "Low stress films of cyclized polybutadiene dielectrics by vacuum annealing"; Oct. 21-22, 1986; pp. 96-102.	
		Allen, Mark G.; Senturia, Stephen D.; "Measurement of polyimide interlayer adhesion using microfabricated structures"; 1988; pp. 352-356.	
ML		Kochugova, I.V.; Nikolaeva, L.V.; Vakser, N.M., (M.I. Kalinin Leningrad Polytechnic Institute (USSR); "Electrophysical investigation of thin-layered inorganic coatings"; 1989; pp. 826-828.	

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